

Defect-oriented test generation using probabilistic estimation

Cibakova, Tatiana; Fischerova, Maria; Gramatova, Elena; Kuzmicz, W.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes**
Proceedings of the 8th International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2001 : Zakopane,
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Finite state machines with datapath partitioning for low power synthesis

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Laboratory training for teaching design and test of digital circuits

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